



<b>Title of Change:</b>	Update of FPCN21451X – Correction of the Test Change box selection in the Change Category section and the addition of 2 Qualification Vehicles in the Reliability Data Summary table.			
<b>Proposed first ship date:</b>	20 December 2016			
<b>Contact information:</b>	Contact your local ON Semiconductor Sales Office or <masitah.aznam@onsemi.com>			
<b>Samples:</b>	Contact your local ON Semiconductor Sales Office			
<b>Additional Reliability Data:</b>	Contact your local ON Semiconductor Sales Office or <masitah.aznam@onsemi.com>			
<b>Type of notification:</b>	ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>.			
<b>Change category:</b>	<input type="checkbox"/> Wafer Fab Change <input type="checkbox"/> Assembly Change <input type="checkbox"/> Test Change <input checked="" type="checkbox"/> Other <u>Plating Change</u>			
<b>Change Sub-Category(s):</b>	<input checked="" type="checkbox"/> Manufacturing Site Change/Addition <input type="checkbox"/> Manufacturing Process Change		<input type="checkbox"/> Material Change <input type="checkbox"/> Product specific change	
			<input checked="" type="checkbox"/> Datasheet/Product Doc change <input checked="" type="checkbox"/> Shipping/Packaging/Marking <input type="checkbox"/> Other: _____	
<b>Sites Affected:</b>	<input type="checkbox"/> All site(s) <input type="checkbox"/> not applicable		<input checked="" type="checkbox"/> ON Semiconductor site(s) : ON Niigata, Japan <input type="checkbox"/> External Foundry/Subcon site(s)	
<b>Description and Purpose:</b>				
This Update Notification is issued to inform customer on the following updates:				
<ul style="list-style-type: none"> <li>• Test Change box in the Change Category section was incorrectly selected. No Test site change is being announced.</li> <li>• 2 Qual Vehicles (<b>NSR20F40NXT5G</b> and <b>NSR02L30NXT5G</b>) were added to the Reliability Data Summary which unintentionally missed out from the previous FPCN21451X.</li> <li>• Clarification that the full list of impacted parts is reflected in this Update Notice because some parts were included in the initial FPCN21451X distribution but unintentionally omitted from the Generic PCN document.</li> </ul>				
The <b>FPCN21451X</b> was initially released in September 2016 to notify customers on the plans to transfer of DSN2 Schottky plating site from existing external foundry facility to existing internal manufacturing site in Niigata, Japan.				
<b>Reliability Data Summary:</b>				
QV DEVICE NAME : NSR10F40NXT5G, <b>NSR20F40NXT5G</b> , <b>NSR02L30NXT5G</b> PACKAGE: DSN2				
Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=90°C, 80% max rated V	1008 hrs	0/240
TC	JESD22-A104	Ta= -_40°C to +125°C	850cyc	0/240
H3TRB	JESD22-A101	85°C, 85% RH, 80%bias	1008 hrs	0/240
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/240

**Electrical Characteristic Summary:**

Three temperature characterization and ESD performance meet datasheet specification. Detail of Electrical characterization result is available upon request.

**List of Affected Standard Parts:**

Part Number	Qualification Vehicle
NSR02L30NXT5G	NSR02L30NXT5G
NSR02F30NXT5G	NSR02L30NXT5G
NSR05F40NXT5G	NSR10F40NXT5G
NSR10F20NXT5G	NSR10F40NXT5G
NSR10F30NXT5G	NSR10F40NXT5G
SNSR20F20NXT5G	NSR20F40NXT5G
NSR05F30QNXT5G	NSR10F40NXT5G
NSR10F30QNXT5G	NSR10F40NXT5G
NSR20F30QNXT5G	NSR20F40NXT5G
NSR05F40QNXT5G	NSR10F40NXT5G
NSR10F40QNXT5G	NSR10F40NXT5G